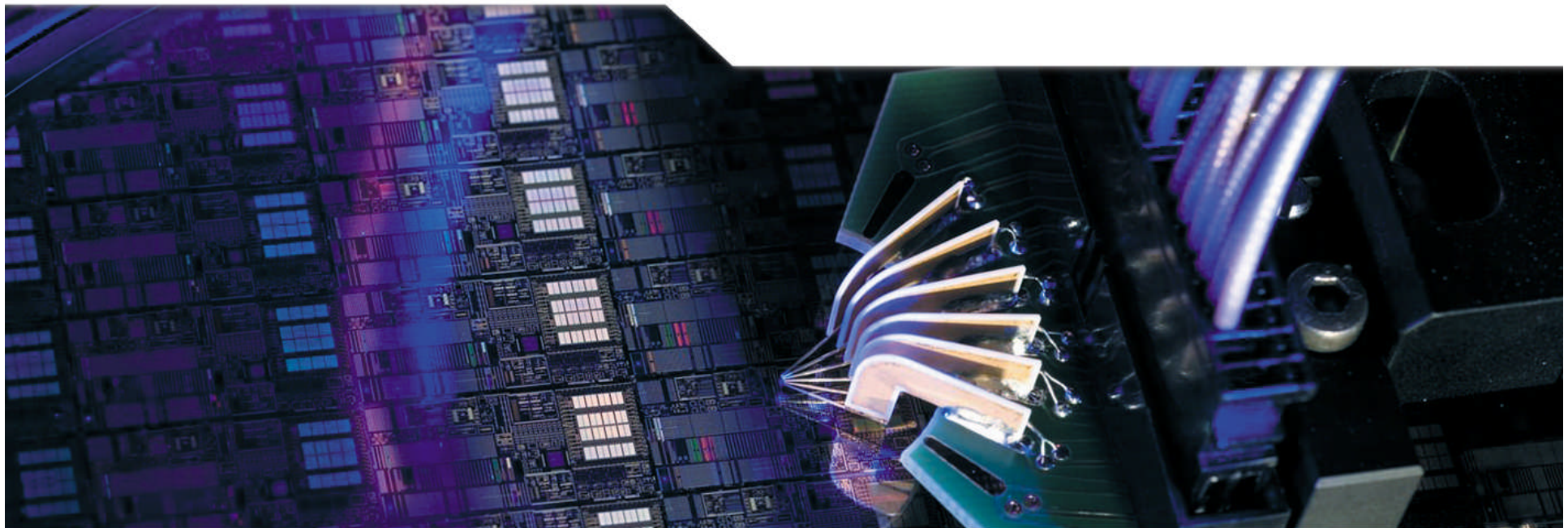




DOTSEVEN WORKSHOP

Physics and Reliability

University of Bordeaux
3251 Cours de la Libération
IMS, Bat 31, Amphithéâtre Jean-Paul Dom
Bordeaux, France



A European Project supported within the Seventh Framework Programme for Research and Technological Development





Programme

- Opening and Welcome – 9:00am
 - *Thomas Zimmer, University of Bordeaux*
- Session 1: Physics based device simulation – 9:15-10:45am
 - *Christoph Jungemann, RWTH Aachen University*
- Coffee Break – 10:45-11:00am
- Session 2: Safe operating limits of SiGe-THz devices – 11:00-12:30am
 - *Anjan Chakravorty, IIT Madras, India, now guest professor at the University of Bordeaux*
- Lunch Break: 12:30-14:00pm



Programme

- Session 3: Reliability of SiGe-THz devices – 14:00-15:30pm
 - *Grazia Sasso, University of Naples, Italy*
- Coffee Break – 15:30-15:45
- Session 4: Reliability aware circuit design – 15:45-17:15pm
 - *Cristell Maneux, University of Bordeaux, France*
- End of SiGe-THz device Tutorial – 17:30pm